



**International
Standard**

ISO/IEC 10373-6

**Cards and security devices for
personal identification — Test
methods —**

**Part 6:
Contactless proximity objects**

*Cartes et dispositifs de sécurité pour l'identification
personnelle — Méthodes d'essai —*

Partie 6: Objets sans contact de proximité

**Fifth edition
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Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work.

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This document was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, SC 17, *Cards and security devices for personal identification*.

This fifth edition cancels and replaces the fourth edition (ISO/IEC 10373-6:2020), which has been technically revised. It also incorporates the Amendment ISO/IEC 10373-6:2020/Amd.2:2020.

The main changes are as follows:

- addition of explicit RFU reception test methods;
- modifications of the PICC transmission test methods;
- simplifications of the impedance matching networks; and
- corrections of the conformance test plan.

A list of all the parts in the ISO/IEC 10373 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html and www.iec.ch/national-committees.

Cards and security devices for personal identification — Test methods —

Part 6: Contactless proximity objects

1 Scope

This document defines test methods which are specific to proximity cards and objects, proximity coupling devices and proximity extended devices, defined in ISO/IEC 14443-1, ISO/IEC 14443-2, ISO/IEC 14443-3 and ISO/IEC 14443-4.

NOTE Test methods defined in this document are intended to be performed separately. A given proximity card or object, proximity coupling device or proximity extended device, is not required to pass through all the tests sequentially.

The conformance test plan defined in [Annex O](#) specifies the list of tests required for each part of the ISO/IEC 14443 series.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/IEC 7810, *Identification cards — Physical characteristics*

ISO/IEC 14443-1:2018, *Cards and security devices for personal identification — Contactless proximity objects — Part 1: Physical characteristics*

ISO/IEC 14443-2:2020, *Cards and security devices for personal identification — Contactless proximity objects — Part 2: Radio frequency power and signal interface*

ISO/IEC 14443-3:2018, *Cards and security devices for personal identification — Contactless proximity objects — Part 3: Initialization and anticollision*

ISO/IEC 14443-4:2018, *Cards and security devices for personal identification — Contactless proximity objects — Part 4: Transmission protocol*